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ESTIMATED CONFERENCE FEE

The Conference Fee (covering participation in lectures and poster presentations, the book of abstracts, proceedings, lunches, the conference dinner and social events) will be:

250 Euro if paid before 20 March 2005
300 Euro if paid after 20 March 2005

ACCOMMODATION

The price of the accommodation in the *Zajazd Piastowski Hotel* (where the conference will be held) and other hotels and pensions located in the near neighbourhood ranges:

from **15 Euro/night in a double room**
to **70 Euro/night in an apartment**



CONFERENCE DEADLINES

Pre-registration	15 October 2004
Submission of abstract	15 January 2005
Acceptance information	28 February 2005
Registration, payment	20 March 2005
Hotel reservation	20 March 2005
Late reservation (+15%)	after 20 March 2005

CONFERENCE SECRETARIAT:

Institute of Electron Technology
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XII INTERNATIONAL CONFERENCE ON ELECTRON MICROSCOPY OF SOLIDS



Organized by

Institute of Electron Technology,
Warsaw, Poland

Polish Society for Microscopy

Polish Materials Society

FIRST CIRCULAR

Kazimierz Dolny
5-9 June 2005

XII INTERNATIONAL CONFERENCE ON ELECTRON MICROSCOPY OF SOLIDS

ORGANIZING COMMITTEE

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Jacek RATAJCZAK (Secretary)
Andrzej CZERWIŃSKI, Adam ŁASZCZ,
Mariusz PŁUSKA, Marek WZOREK

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Danuta STRÓŻ
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Michał ŻELECHOWER

SCOPE OF THE CONFERENCE

The scope of the EM'2005 is to provide an overview of present achievements in electron microscopy and to highlight recent applications in physics, chemistry and materials science. The scientific program contains sessions of two categories: (i) instrumentation and methodology and (ii) application of EM in materials science. The first category covers sessions like: TEM specimen preparation, analytical TEM (EFTEM, EELS), analytical SEM (EDS, CL, EBIC), electron diffraction/electron crystallography, image interpretation and analysis, and high resolution TEM. The second category comprises the application of electron microscopy to study a wide range of materials like metals and alloys, electronic materials, ceramics, polymers and composites, magnetic materials, amorphous materials, thin films as well as materials and structures for nanotechnology.

VENUE

The conference will be held in Kazimierz Dolny (Poland). The beautiful town of Kazimierz Dolny, situated on the Lublin plateau, lies on the right bank of the river Vistula on its way to the Baltic Sea. Because of its attractive position, its rich history, its picturesque medieval houses, wonderful architecture and kind climate, Kazimierz Dolny is known not only in Poland but also abroad. Both the urban architecture as well as the attractive landscape of Kazimierz Dolny and the surrounding countryside have become well known in Poland and beyond its borders.

PRELIMINARY LIST OF INVITED SPEAKERS

Guillaume BASTIN (The Netherlands) – *Electron Probe Microanalysis with Non-perpendicular Incidence of the Electron Beam*

Philippe BUFFAT (Switzerland) – *The Limits of Nanophase Identification Using EDS/EELS Spectrometries and Electron Diffraction Techniques*

Anders GUSTAFSSON (Sweden) – *Cathodoluminescence Studies of Nano-structured Semiconductors*

Ferdinand HOFER (Austria) – *Energy-filtering Transmission Electron Microscopy at the Frontier of Spatial and Energy Resolution*

Wolfgang JÄGER (Germany) – *Metal-Induced Nanostructures on Surfaces of Layered Chalcogenides*

Janos LABAR (Hungary) – *Quantitative Phase Analysis of Nanocrystalline Samples Based on SAED*

Paul MIDGLEY (UK) – *Electron Tomography of Nanoparticles and Nanocrystals*

Jean Paul MORNIROLI (France) – *CBED and LACBED Characterization of Crystal Defects*

Wolfgang NEUMANN (Germany) – *Quantitative HRTEM*

Fritz PHILLIPP (Germany) – *In-Situ Atomic Resolution Electron Microscopy*

Makoto SHIOJIRI (Japan) – *HAADF-STEM Imaging and Microscopy Observations of Heterostructures in Electronics Devices*

Robert SINCLAIR (USA) – *In Situ Crystallization and Measurement of Metal Oxide Thin Films for High-k Dielectric Applications*

Horst STRUNK (Germany) – *Cathodoluminescence in Transmission Electron Microscopy*

Gustaaf Van TENDELOO (Belgium) – *When? Why? How? Different are Thin Films from Bulk*

Knut URBAN (Germany) – *Aberration Corrected Transmission Electron Microscopy*

Following speakers also agreed to give a lecture at our conference:

Yoshihiko HIROTSU (Japan) Genevieve NIHOUL (France)
Martin HYTCH (France) Richard PORTIER (France)

CONFERENCE PROCEEDINGS

Organizing Committee intends to publish the book of abstracts before the conference as well as the conference proceedings afterwards. The proceedings will be published as one or more Special Issues of the Journal of Microscopy (Blackwell Publishing). The manuscript should be submitted at the conference desk.

Preliminary Registration Form

XII International Conference on Electron Microscopy of Solids

Please fill in this form with capital letters and return by post, fax or e-mail. You can also register on-line using our web pages <http://www.ite.waw.pl/em2005/>

Mr Ms

Given names:

Surname:

Titles:

Affiliation:

Address:

Phone:

Fax:

E-mail:

Preliminary title of presentation:

Preferred way of presentation: oral poster

Only limited number of papers will be assigned to oral sessions.